

LCIE SUD EST
Laboratoire de Moirans
Z.I. Centr'Alp
170, Rue de Chatagnon
38430 MOIRANS - FRANCE

GENERAL INFORMATION

FCCID: YCP-32WB1MMCH01

1.1. Product description

Features

- Integrated chip antenna, and option for external antenna
- Bluetooth® Low Energy 5.4 certified
- Supports 2 Mbits/s
- Frequency band: 2400 to 2483.5 MHz
- Advertising extension
- TX output power up to +5.5 dBm
- RX sensitivity: -96 dBm (1 Mbps)
- Range: TBD
- Dedicated Arm® Cortex®-M0+ for radio and security tasks
- Dedicated Arm[®] Cortex[®]-M4 CPU with FPU and ART (adaptative real-time accelerator), up to 64 MHz speed
- 320-Kbyte flash memory, 48-Kbyte SRAM
- Fully integrated BOM, including 32 MHz radio and 32 kHz RTC crystals
- Integrated SMPS
- Ultra-low power modes for battery longevity
- 27 GPIOs
- SWD, JTAG
- Integrated IPD for best-in-class and reliable antenna matching
- V_{DD} range: 1.71 to 3.6 V
- Temperature range: -40 to 85 °C
- Built-in security features, such as secure firmware installation (SFI) for radio stack, PKA, AES 256-bit, RNG, PCROP, CRC, 96-bit UID, possibility to derive 48-bit UEI

Description

The STM32WB1MMC is an ultralow power, small form factor, certified 2.4 GHz wireless module, supporting Bluetooth® Low Energy 5.4. Based on the STM32WB15CCY wireless microcontroller, it provides best-in-class RF performance thanks to its good receiver sensitivity and a high output power signal. Its low power features enable extended battery life time, small coin-cell batteries, or energy harvesting.

The STM32WB1MMC requires no RF expertise, and is the best way to speed up the application development and to reduce the associated costs. The module is completely protocol stack royalty-free.



LCIE SUD EST

Laboratoire de Moirans Z.I. Centr'Alp 170, Rue de Chatagnon 38430 MOIRANS - FRANCE

Tested System Details

Equi	ipme	nt i	infori	matic	on (I	<u>/lanut</u>	act	<u>turer</u>	Dec	larat	ion	Ì
										_		

Equipment information (manuf	acturer Declaration)	<u>.</u>						
Bluetooth LE Type:	☑ BLE		□ v4.0	□ v4.2		□ v5.0		
Frequency band:	[2400 – 2483.5] MHz							
Spectrum Modulation:	☑ DSSS (Tested like it)							
Number of Channel:	40							
Spacing channel:	2MHz							
Channel bandwidth:	☑ 1MHz			☑ 2MHz				
Antenna Type:	□ Integral		□ Ext	ternal	☐ Dedicated			
Antenna connector:	☐ Yes		☑ No		☐ Temporary for test			
	1							
Transmit chains:	Single antenna							
	Gain: 1.9dBi							
Beam forming gain:	No							
Receiver chains	1							
Type of equipment:		☐ Plug-in		☐ Combined				
Ad-Hoc mode:	□ Yes			☑ No				
Adaptivity mode:				mode		□ No		
Adaptivity mode.	Clear Cha	ssessment Tim						
Duty cycle:		☐ Intermi	☐ Intermittent duty		☐ 100% duty			
Equipment type:				☐ Pre-production model				
	Tmin:	□ -20°C		□ 0°C				
Operating temperature range:	Tnom:			20°C				
	Tmax:		□ 35°C	□ 55°C				
Type of power source:	☐ AC power supply		☐ DC pov			☐ Battery		
Operating voltage range:	Vnom:		□ 230\	/50Hz		☑ 3Vdc		
	☐ Yes (The geog							
	determined by the							
Geo-location capability:	accessible to the er		☑ No					
	section 4.3.2.12.2							
	V2.2.2 s	(a)						

1.3. **Test Methodology**

Both conducted and radiated testing were performed according to the procedures in ANSI C63.4 or/and ANSI C63.10, FCC Part 15 SubPart 15C.

Radiated testing was performed at an antenna to EUT distance of 10 meters. During testing, all equipment's and cables were moved relative to each other in order to identify the worst case set-up.

Test facility 1.4.

Tests have been performed: February 13, 2023 to February 14, 2023

This test facility has been fully described in a report and accepted by FCC as compliant with the radiated and AC line conducted test site criteria in ANSI C63.4 or/and ANSI C63.10.

This test facility has also been accredited by COFRAC (French accreditation authority for European Union test lab accreditation organization) according to NF EN ISO/IEC 17025, as compliant with test site criteria and competence in 47 CFR Part 15/ANSI C63.4 and EN55032/CISPR32 norms for 89/336/EEC European EMC Directive application. All pertinent data for this test facility remains unchanged.